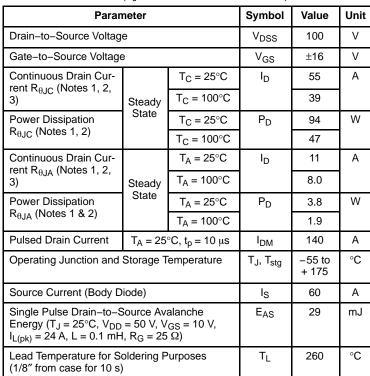
## **Power MOSFET** 100 V, 15 mΩ, 55 A, Single N–Channel

#### Features

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- NVMFS6B14NWF Wettable Flank Option for Enhanced Optical Inspection
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise noted)



Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{ extsf{ heta}JC}$	1.6	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{ extsf{ heta}JA}$	40	

1. The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.

2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.

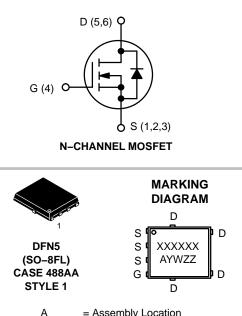
3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.

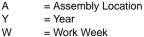


## **ON Semiconductor®**

#### www.onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
100 V	15 mΩ @ 10 V	55 A





ZZ = Lot Traceability

#### **ORDERING INFORMATION**

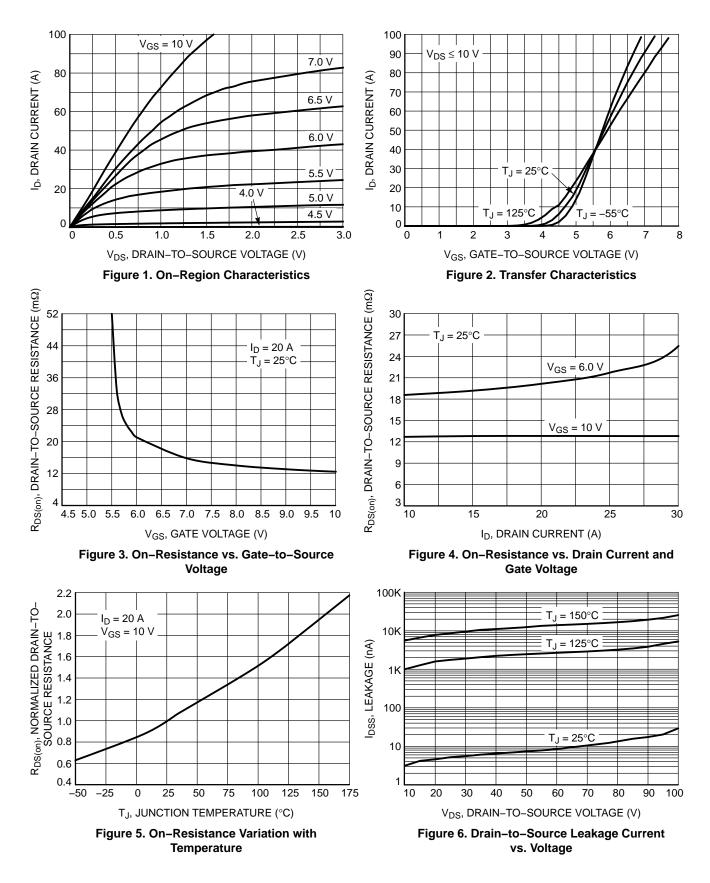
See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}$ C unless otherwise specified)

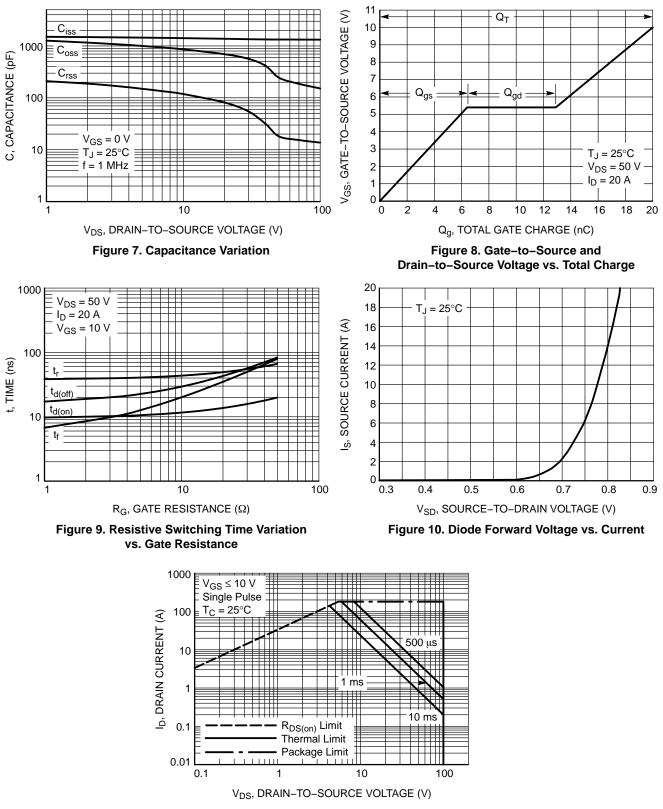
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS					-		-
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS}$ = 0 V, I <sub>D</sub> = 250 $\mu$ A		100			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				80		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V,$	$T_J = 25^{\circ}C$			10	μΑ
	V <sub>DS</sub> = 8	V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			100	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS}$	<sub>S</sub> = 16 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D =$	= 250 μA	2.0		4.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-8.5		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		12.2	15	mΩ
CHARGES, CAPACITANCES & GATE RESIS	STANCE				-		-
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 50 V			1300		pF
Output Capacitance	C <sub>OSS</sub>				260		
Reverse Transfer Capacitance	C <sub>RSS</sub>				18		
Total Gate Charge	Q <sub>G(TOT)</sub>				20		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 50 \text{ V}; I_D = 20 \text{ A}$ $T_J = 25^{\circ}\text{C}$			2.2		nC
Gate-to-Source Charge	Q <sub>GS</sub>				6.4		
Gate-to-Drain Charge	Q <sub>GD</sub>				6.5		
Plateau Voltage	V <sub>GP</sub>				5.4		V
Gate Resistance	R <sub>G</sub>				1.0		Ω
SWITCHING CHARACTERISTICS (Note 5)							
Turn-On Delay Time	t <sub>d(ON)</sub>				9.6		
Rise Time	t <sub>r</sub>	$\begin{array}{l} V_{GS} = 10 \; V,  V_{DS} = 50 \; V, \\ I_{D} = 20 \; A,  R_{G} = 1.0 \; \Omega \end{array}$			39		ns
Turn–Off Delay Time	t <sub>d(OFF)</sub>				16.6		
Fall Time	t <sub>f</sub>				6.8		
DRAIN-SOURCE DIODE CHARACTERISTIC	s						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 20 A	$T_J = 25^{\circ}C$		0.83	1.2	v
			T <sub>J</sub> = 125°C		0.8		
Reverse Recovery Time	t <sub>RR</sub>	V <sub>GS</sub> = 0 V, dIS/dt = 100 A/μs, I <sub>S</sub> = 20 A			45		ns
Charge Time	ta				23		
Discharge Time	t <sub>b</sub>				22		
Reverse Recovery Charge	Q <sub>RR</sub>				50		nC

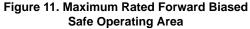
Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Pulse Test: pulse width  $\leq 300 \,\mu$ s, duty cycle  $\leq 2\%$ . 5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**

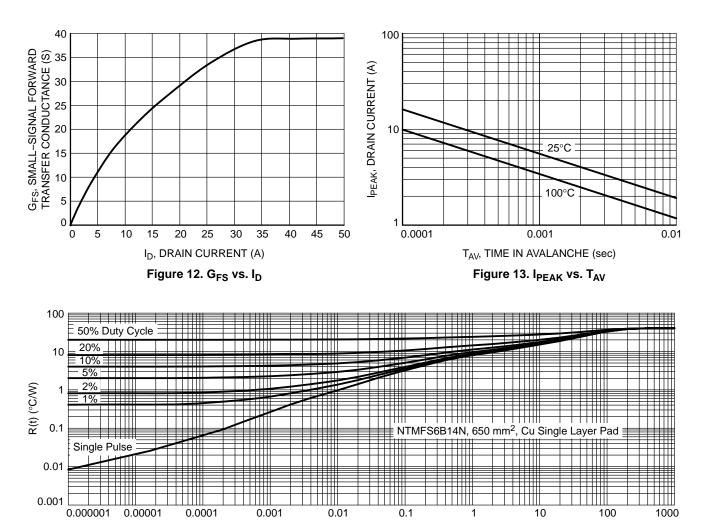


#### **TYPICAL CHARACTERISTICS**





#### **TYPICAL CHARACTERISTICS**



PULSE TIME (sec)

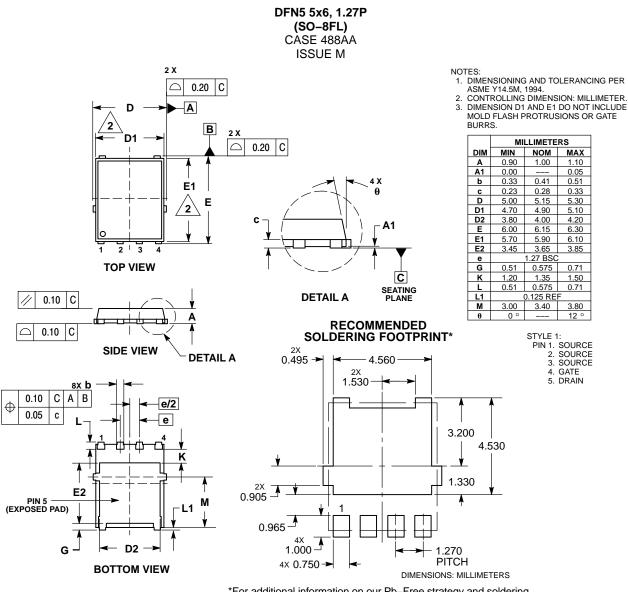
Figure 14. Thermal Response

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMFS6B14NT1G	6B14N	DFN5 (Pb–Free)	1500 / Tape & Reel
NVMFS6B14NWFT1G	6B14WF	DFN5 (Pb–Free, Wettable Flanks)	1500 / Tape & Reel
NVMFS6B14NT3G	6B14N	DFN5 (Pb–Free)	5000 / Tape & Reel
NVMFS6B14NWFT3G	6B14WF	DFN5 (Pb–Free, Wettable Flanks)	5000 / Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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#### PUBLICATION ORDERING INFORMATION

#### LITERATURE FULFILLMENT:

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For additional information, please contact your local Sales Representative